# **Quad Bus Buffer**

# with 3-State Control Inputs

The MC74VHCT126A is a high speed CMOS quad bus buffer fabricated with silicon gate CMOS technology. It achieves noninverting high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The MC74VHCT126A requires the 3-state control input (OE) to be set Low to place the output into high impedance.

The VHCT inputs are compatible with TTL levels. This device can be used as a level converter for interfacing 3.3 V to 5.0 V, because it has full 5.0 V CMOS level output swings.

The VHCT126A input structures provide protection when voltages between 0 V and 5.5 V are applied, regardless of the supply voltage. The output structures also provide protection when  $V_{CC}=0$  V. These input and output structures help prevent device destruction caused by supply voltage — input/output voltage mismatch, battery backup, hot insertion, etc.

The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output. The inputs tolerate voltages up to 7.0 V, allowing the interface of 5.0 V systems to 3.0 V systems.

#### **Features**

- High Speed:  $t_{PD} = 3.8 \text{ ns}$  (Typ) at  $V_{CC} = 5.0 \text{ V}$
- Low Power Dissipation:  $I_{CC} = 4.0 \mu A$  (Max) at  $T_A = 25$ °C
- TTL-Compatible Inputs:  $V_{IL} = 0.8 \text{ V}$ ;  $V_{IH} = 2.0 \text{ V}$
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Designed for 2.0 V to 5.5 V Operating Range
- Low Noise:  $V_{OLP} = 0.8 \text{ V (Max)}$
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300 mA
- ESD Performance: HBM > 2000 V; Machine Model > 200 V
- Chip Complexity: 72 FETs or 18 Equivalent Gates
- NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant



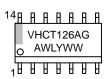
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#### MARKING DIAGRAMS



SOIC-14 D SUFFIX CASE 751A





TSSOP-14 DT SUFFIX CASE 948G



A = Assembly Location

WL, L = Wafer Lot Y = Year WW, W = Work Week G or = Pb-Free Package

(Note: Microdot may be in either location)

See Applications Note #AND8004/D for date code and traceability information.

#### **FUNCTION TABLE**

	VHCT126A				
I	nputs	Outputs			
А	OE	Y			
H L X	H H L	H L Z			

#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

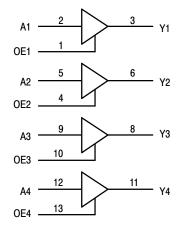


Figure 1. LOGIC DIAGRAM Active-High Output Enables

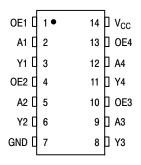


Figure 2. PIN ASSIGNMENT

#### **MAXIMUM RATINGS**

Rating		Symbol	Value	Unit
DC Supply Voltage		V <sub>CC</sub>	- 0.5 to + 7.0	٧
DC Input Voltage		V <sub>in</sub>	- 0.5 to + 7.0	٧
DC Output Voltage	Output in 3–State High or Low State	V <sub>out</sub>	- 0.5 to + 7.0 - 0.5 to V <sub>CC</sub> + 0.5	٧
Input Diode Current		I <sub>IK</sub>	- 20	mA
Output Diode Current (V <sub>OUT</sub> <	GND; V <sub>OUT</sub> > V <sub>CC</sub> )	lok	± 20	mA
DC Output Current, per Pin		l <sub>out</sub>	± 25	mA
DC Supply Current, V <sub>CC</sub> and C	SND Pins	I <sub>CC</sub>	± 75	mA
Power Dissipation in Still Air,	SOIC Packages† TSSOP Package†	P <sub>D</sub>	500 450	mW
Storage Temperature		T <sub>stg</sub>	- 65 to + 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

†Derating — SOIC Packages: – 7 mW/°C from 65° to 125°C TSSOP Package: – 6.1 mW/°C from 65° to 125°C

#### RECOMMENDED OPERATING CONDITIONS

Param	eter	Symbol	Min	Max	Unit
DC Supply Voltage		V <sub>CC</sub>	4.5	5.5	V
DC Input Voltage		V <sub>in</sub>	0	5.5	V
DC Output Voltage	Output in 3–State High or Low State	V <sub>out</sub>	0 0	5.5 V <sub>CC</sub>	V
Operating Temperature		T <sub>A</sub>	- 40	+ 85	°C
Input Rise and Fall Time	$V_{CC} = 5.0 \text{ V } \pm 0.5 \text{ V}$	t <sub>r</sub> , t <sub>f</sub>	0	20	ns/V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq$  ( $V_{in}$  or  $V_{out}$ )  $\leq$   $V_{CC}$ .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V<sub>CC</sub>). Unused outputs must be left open.

#### DC ELECTRICAL CHARACTERISTICS

			v <sub>cc</sub>	T,	<sub>4</sub> = 25°	С	T <sub>A</sub> ≤	85°C	<b>T</b> <sub>A</sub> ≤ '	125°C	
Parameter	Test Conditions	Symbol	(V)	Min	Тур	Max	Min	Max	Min	Max	Unit
Minimum High-Level Input Voltage		V <sub>IH</sub>	3.0 4.5 5.5	1.2 2.0 2.0			1.2 2.0 2.0		1.2 2.0 2.0		V
Maximum Low–Level Input Voltage		V <sub>IL</sub>	3.0 4.5 5.5			0.53 0.8 0.8		0.53 0.8 0.8		0.53 0.8 0.8	V
Minimum High–Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -50 \mu A$	V <sub>OH</sub>	3.0 4.5	2.9 4.4	3.0 4.5		2.9 4.4		2.9 4.4		V
$V_{IN} = V_{IH} \text{ or } V_{IL}$	$\begin{aligned} &V_{\text{IN}} = V_{\text{IH}} \text{ or } V_{\text{IL}} \\ &I_{\text{OH}} = -4.0 \text{ mA} \\ &I_{\text{OH}} = -8.0 \text{ mA} \end{aligned}$		3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66		
Maximum Low-Level Output Voltage VIN = VIH or VII	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 50  \mu\text{A}$	V <sub>OL</sub>	3.0 4.5		0.0 0.0	0.1 0.1		0.1 0.1		0.1 0.1	V
NIN = AIH OI AIL	$\begin{aligned} V_{IN} &= V_{IH} \text{ or } V_{IL} \\ I_{OL} &= 4.0 \text{ mA} \\ I_{OL} &= 8.0 \text{ mA} \end{aligned}$		3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52	
Maximum Input Leakage Current	V <sub>IN</sub> = 5.5 V or GND	I <sub>IN</sub>	0 to 5.5			± 0.1		± 1.0		± 1.0	μΑ
Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	I <sub>CC</sub>	5.5			2.0		20		40	μА
Quiescent Supply Current	Input: V <sub>IN</sub> = 3.4 V	I <sub>CCT</sub>	5.5			1.35		1.50		1.65	mA
Maximum 3–State Leakage Current	$V_{IN} = V_{IH} \text{ or } V_{I}$ $V_{OUT} = V_{CC} \text{ or GND}$	l <sub>OZ</sub>	5.5			±0.2 5		±2.5		±2.5	μΑ
Output Leakage Current	V <sub>OUT</sub> = 5.5 V	I <sub>OPD</sub>	0.0			0.5		5.0		10	μΑ

# AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0 \text{ ns}$ )

			T <sub>A</sub> = 25°C		<b>T</b> <sub>A</sub> = ≤	≤ 85°C	<b>T</b> <sub>A</sub> ≤ '	125°C		
Parameter	Test Conditions	Symbol	Min	Тур	Max	Min	Max	Min	Max	Unit
Maximum Propagation Delay, A to Y	$V_{CC} = 3.3 \pm 0.3 \text{ V}$ $C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$	t <sub>PLH</sub> , t <sub>PHL</sub>		5.6 8.1	8.0 11.5	1.0 1.0	9.5 13.0		12.0 16.0	ns
	$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 15 \text{ pF}$ $C_L = 50 \text{ pF}$			3.8 5.3	5.5 7.5	1.0 1.0	6.5 8.5		8.5 10.5	
Maximum Output Enable TIme, OE to Y	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	t <sub>PZL</sub> , t <sub>PZH</sub>		5.4 7.9	8.0 11.5	1.0 1.0	9.5 13.0		11.5 15.0	ns
	$\begin{array}{cccccccccccccccccccccccccccccccccccc$			3.6 5.1	5.1 7.1	1.0 1.0	6.0 8.0		7.5 9.5	
Maximum Output Disable Time, OE to Y	$\begin{array}{c} V_{CC} = 3.3 \pm 0.3 \ V  C_L = 50 \ pF \\ R_L = 1.0 \ k\Omega \end{array}$	t <sub>PLZ</sub> , t <sub>PHZ</sub>		9.5	13.2	1.0	15.0		18.0	ns
	$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 50 \text{ pF}$ $R_L = 1.0 \text{ k}\Omega$			6.1	8.8	1.0	10.0		12.0	
Output-to-Output Skew	$V_{CC} = 3.3 \pm 0.3 \text{ V}$ $C_L = 50 \text{ pF}$ (Note 1)	t <sub>OSLH</sub> , t <sub>OSHL</sub>			1.5		1.5		2.0	ns
	$V_{CC} = 5.0 \pm 0.5 \text{ V}$ $C_L = 50 \text{ pF}$ (Note 1)				1.0		1.0		1.5	
Maximum Input Capacitance		C <sub>in</sub>		4	10		10		10	pF
Maximum Three–State Output Capacitance (Output in High Impedance State)		C <sub>out</sub>		6						pF
	•		Typical @ 25°C, V <sub>CC</sub> = 5.0V							
Power Dissipation Capacitance (N	Note 2)	C <sub>PD</sub>				15				pF

Parameter guaranteed by design. t<sub>OSLH</sub> = |t<sub>PLHm</sub> - t<sub>PLHn</sub>|, t<sub>OSHL</sub> = |t<sub>PHLm</sub> - t<sub>PHLn</sub>|.
 C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: I<sub>CC(OPR)</sub> = C<sub>PD</sub> • V<sub>CC</sub> • f<sub>in</sub> + I<sub>CC</sub>/4 (per buffer). C<sub>PD</sub> is used to determine the no–load dynamic power consumption; P<sub>D</sub> = C<sub>PD</sub> • V<sub>CC</sub><sup>2</sup> • f<sub>in</sub> + I<sub>CC</sub> • V<sub>CC</sub>.

## **NOISE CHARACTERISTICS** (Input $t_r = t_f = 3.0$ ns, $C_L = 50$ pF, $V_{CC} = 5.0$ V)

		T <sub>A</sub> = 25°C		
Characteristic	Symbol	Тур	Max	Unit
Quiet Output Maximum Dynamic V <sub>OL</sub>	V <sub>OLP</sub>	0.3	0.8	V
Quiet Output Minimum Dynamic V <sub>OL</sub>	V <sub>OLV</sub>	- 0.3	- 0.8	V
Minimum High Level Dynamic Input Voltage	V <sub>IHD</sub>		3.5	V
Maximum Low Level Dynamic Input Voltage	V <sub>ILD</sub>		1.5	V

#### **SWITCHING WAVEFORMS**

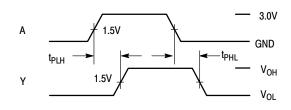


Figure 3.

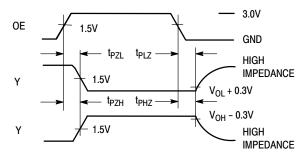
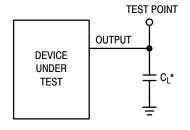


Figure 4.



\*Includes all probe and jig capacitance
Figure 5. Test Circuit

DEVICE UNDER TEST  $C_L^*$ TEST POINT

OUTPUT  $1 \text{ k}\Omega$ OUTPUT  $1 \text{ k}\Omega$   $C_L^*$ CONNECT TO  $V_{CC}$  WHEN TESTING  $t_{PLZ}$  AND  $t_{PZL}$ . CONNECT TO GND WHEN TESTING  $t_{PHZ}$  AND  $t_{PZH}$ .

\*Includes all probe and jig capacitance

Figure 6. Test Circuit

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
MC74VHCT126ADR2G	SOIC-14 (Pb-Free)	2500 / Tape & Reel
M74VHCT126ADTR2G	TSSOP-14 (Pb-Free)	2500 / Tape & Reel
NLVVHCT126ADTR2G*	TSSOP-14 (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

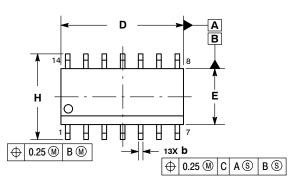
<sup>\*</sup>NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

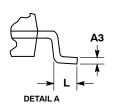


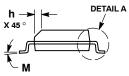
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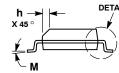
SOIC-14 NB CASE 751A-03 ISSUE L

**DATE 03 FEB 2016** 





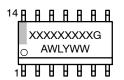




- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
  - ASME Y14.5M, 1994.
    CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT
- MAXIMUM MATERIAL CONDITION.
  DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	1.35	1.75	0.054	0.068	
A1	0.10	0.25	0.004	0.010	
АЗ	0.19	0.25	0.008	0.010	
b	0.35	0.49	0.014	0.019	
D	8.55	8.75	0.337	0.344	
Е	3.80	4.00	0.150	0.157	
е	1.27	1.27 BSC 0.05		BSC	
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.019	
L	0.40	1.25	0.016	0.049	
M	0 °	7°	0 °	7 °	

#### **GENERIC MARKING DIAGRAM\***

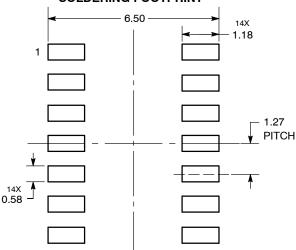


XXXXX = Specific Device Code Α = Assembly Location

WL = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator. "G" or microdot " ■". may or may not be present.

# **SOLDERING FOOTPRINT\***



DIMENSIONS: MILLIMETERS

C SEATING PLANE

#### **STYLES ON PAGE 2**

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<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

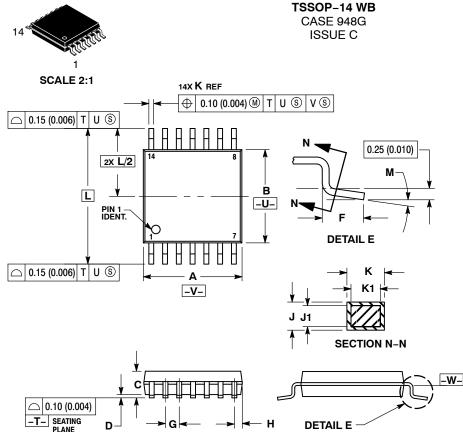
## SOIC-14 CASE 751A-03 ISSUE L

## DATE 03 FEB 2016

STYLE 1: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. NO CONNECTION 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. NO CONNECTION 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 2: CANCELLED	STYLE 3: PIN 1. NO CONNECTION 2. ANODE 3. ANODE 4. NO CONNECTION 5. ANODE 6. NO CONNECTION 7. ANODE 8. ANODE 9. ANODE 10. NO CONNECTION 11. ANODE 12. ANODE 13. NO CONNECTION 14. COMMON CATHODE	STYLE 4: PIN 1. NO CONNECTION 2. CATHODE 3. CATHODE 4. NO CONNECTION 5. CATHODE 6. NO CONNECTION 7. CATHODE 8. CATHODE 9. CATHODE 10. NO CONNECTION 11. CATHODE 12. CATHODE 13. NO CONNECTION 14. COMMON ANODE
STYLE 5: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. NO CONNECTION 7. COMMON ANODE 8. COMMON CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 6: PIN 1. CATHODE 2. CATHODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE 7. CATHODE 8. ANODE 9. ANODE 10. ANODE 11. ANODE 12. ANODE 13. ANODE 14. ANODE	STYLE 7: PIN 1. ANODE/CATHODE 2. COMMON ANODE 3. COMMON CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. ANODE/CATHODE 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. COMMON CATHODE 12. COMMON ANODE 13. ANODE/CATHODE 14. ANODE/CATHODE	STYLE 8: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. ANODE/CATHODE 7. COMMON ANODE 8. COMMON ANODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. NO CONNECTION 12. ANODE/CATHODE 13. ANODE/CATHODE 14. COMMON CATHODE

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**SOLDERING FOOTPRINT** 

7.06

14X

1.26

**DATE 17 FEB 2016** 

- NOTES.

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2. CONTROLLING DIMENSION: MILLIMETER.

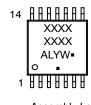
  3. DIMENSION A DOES NOT INCLUDE MOLD
- FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
  DIMENSION B DOES NOT INCLUDE
- INTERLEAD FLASH OR PROTRUSION.
  INTERLEAD FLASH OR PROTRUSION SHALL
- INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.

  5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.

  6. TERMINAL NUMBERS ARE SHOWN FOR DECEDEDIC ONLY
- REFERENCE ONLY.
  DIMENSION A AND B ARE TO BE
- DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026	BSC
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40	BSC	0.252 BSC	
М	0 °	8 °	0 °	8 °

#### **GENERIC MARKING DIAGRAM\***



= Assembly Location

= Wafer Lot = Year

W = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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**DIMENSIONS: MILLIMETERS** 

0.65

**PITCH** 

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